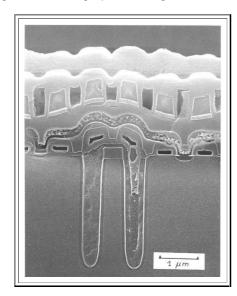
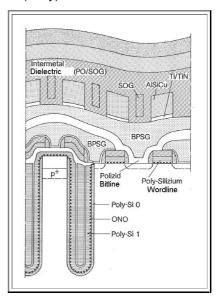
Cross Section of 16 Mbit DRAM and 64 Mbit DRAM

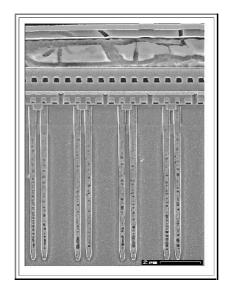
Below a large SEM micrograph showing the cross-section of an (early) 16 Mbit DRAM.





Some explanations:

- The two deep "trenches" (they are <u>really</u> holes) contain the capacitors. There dielectric (with ca. **7 nm** far too thin to be visible) is "**ONO**", a triple layer of Oxide Nitride Oxide.
- The trench os lined with poly-Si as a first electrode and as the second electrode.
- To the left and right two transistor gates are visible. The sources of both transistors is the (poly-Si) electrode
 lining the trench and the diffused areas being contacted by the "Polizid bitline". "Polizid" means a double layer
 of poly-Si and MoSi₂ Molybdenum-silicide.
- The "poly-Si wordline" runs perpendicular to the picture and connects the gates of the transistors
- The "BPSG" layers denote SiO₂ doped with B and P that serves as insulating dielectric. It is essentially a glass.
- Parallel to the word lines are Ti/TiN/AlSiCu lines. They contact the wordlines every once in a while to
 decrease the ohmic resistance. The consist of a layer sequence: Ti, TiN, and Al doped with about 0,5% of Si
 and Cu.
- On top of this first metal layer is another one running across the picture.
- The metals are insulated by the intermetal dielectric composed of plasma-oxide (**PO**) that contains spin-on-glass (**SOG**) in the interstices.
- Below the successor of the 16 Mbit DRAM, the 64 Mbit DRAM from a development stage around about 1996.



The structure is essentially the same, but all layers have been planarized.